

Notice of References Cited	Application/Control No. 10/046,175	Applicant(s)/Patent Under Reexamination WATANABE, YOSHIAKI	
	Examiner Ryan F. Pitaro	Art Unit 2174	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,819,343 B1	11-2004	Sobeski et al.	715/848
*	B	US-2002/0116226 A1	08-2002	Auer et al.	705/3
*	C	US-6,192,282 B1	02-2001	Smith et al.	700/19
*	D	US-2001/0026291	10-2001	Uchida, Toshiharu	345/810
*	E	US-6,195,667 B1	02-2001	Duga et al.	715/513
*	F	US-6,182,116 B1	01-2001	Namma et al.	709/204
*	G	US-2002/0063736 A1	05-2002	Sugimoto, Mika	345/762
*	H	US-6,584,507 B1	06-2003	Bradley et al.	709/229
*	I	US-6,477,576 B2	11-2002	Angwin et al.	709/226
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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